PATENT

Attorney Docket No.: 020859-001310US

Client Reference No.: 3650-P

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Examiner:

Stephen R. Quake et al.

Art Unit:

Application No.:

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §1.97 and

§1.98

Filed:

For: IMPROVED METHOD AND SYSTEM FOR SCANNING APERTURELESS FLUORESCENCE MICROSCOPE

Mail Stop Patent Application Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

The references cited on attached form PTO/SB/08A and PTO/SB/08B are being called to the attention of the Examiner. Copies of the references are enclosed. It is respectfully requested that the cited references be expressly considered during the prosecution of this application, and the references be made of record therein and appear among the "references cited" on any patent to issue therefrom.

As provided for by 37 CFR 1.97(g) and (h), no inference should be made that the information and references cited are prior art merely because they are in this statement and no representation is being made that a search has been conducted or that this statement encompasses all the possible relevant information.

Applicant believes that <u>no fee is required</u> for submission of this statement. However, if a fee is required, the Commissioner is authorized to deduct such fee from the Stephen R. Quake et al. Application No.: Page 2

undersigned's Deposit Account No. 20-1430. Please deduct any additional fees from, or credit any overpayment to, the above-noted Deposit Account.

Respectfully submitted,

Richard T. Ogaw Reg. No. 37,692

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STA	TEMENT	BY APPLICANT	First Named Inventor	Quake, Stephen R., et. al.			
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Page	1	of	Attorney Docket Number	020859-001310US			

U.S. PATENT DOCUMENTS							
		Document Number					
Examiner	Cite No.1	Number Kind Code ² (<i>if known</i>)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
	AA	US-6,002,471	12/14/99	Quake			
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	FOREIGN PATENT DOCUMENTS							
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Approved for use through 04/30/2003. OMB 0651-0031

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	Substitute	for form 144	49/PTO			Complete if Known			
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	STATEMENT BY APPLICANT					First Named Inventor	Quake, Stephen R., et. al.		
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²
	вс	H. GERSEN et al., "Near-field effects in single molecule emission", Journal of Microscopy, Vol. 202, Pt 2, May 2001, pp. 374-378	
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	BF	T.J. YANG et al., "An Apertureless Near-field Microscope for Fluorescence Imaging", Applied Physics Letters, Volume 76, Number 3, January 17, 2000, pp. 378-380	
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